

Notice of References Cited	Application/Control No. 09/831,763	Applicant(s)/Patent Under Reexamination MEYER ET AL.	
	Examiner Brian L. Mutschler	Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,596,148	07-2003	Belongia et al.	205/99
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Choi et al., "Latent Iron in Silicon," Jpn. J. Appl. Phys., Vol. 40 (2001), pp. L915-L917.
*	V	Istratov et al., "Iron and its complexes in silicon," Appl. Phys. A 69 (1999), pp. 13-44.
*	W	Istratov et al., "Iron contamination in silicon technology," Appl. Phys. A 70 (2000), pp. 489-534.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.